

Search Notes

Application/Control No.

10/710,673

Examiner

Hiep Nguyen

Applicant(s)/Patent under
Reexamination

LEE ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST See attachment	10.14.05	Ha